



The supervisory board of the Kestcells Project announces the Workshop1:

“Workshop on Advanced Characterisation Techniques for Thin Film Technologies”

Date: 19th of September, 2013.

Place: Luxembourg

Organizers: University of Luxembourg and Universidad Autónoma de Madrid

Program

Time	Title	Speaker
9:00 - 10:30	Optical characterisation of thin films (T-R, ellipsometry)	Rosalía Serna CSIC, Madrid
10:30 - 10:45	Coffee break	
10:45 - 12:15	Raman spectroscopy of thin films	Victor Izquierdo-Roca IREC, Barcelona
12:15 - 13:15	Lunch break	
13:15 - 14:45	X-ray and neutron scattering methods	Susan Schorr HZB, Free University of Berlin
14:45 - 15:00	Coffee break	
15:00 - 16:30	Photoluminescence	David Regesch University of Luxembourg
16:30 - 16:45	Coffee break	
16:45 - 18:15	Electrical transport measurements	José Manuel Merino Universidad Autonoma Madrid